

<b>Notice of References Cited</b>	Application/Control No. 09/252,925	Applicant(s)/Patent Under Reexamination OHNISHI ET AL.	
	Examiner Hanh Nguyen	Art Unit 2662	Page 1 of 1

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	C	US-5373550	12-1994	Campbell et al.	379/100
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	09/252,925	OHNISHI ET AL.
Examiner	Art Unit	
Tim Spafford	2662	Page 1 of 1

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		09/252,925	Examiner Hanh Nguyen	
			Art Unit 2662	Page 1 of 1

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 Application/Control No.  
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 Reexamination  
 OHNISHI ET AL.

 Examiner  
 Hanh Nguyen

 Art Unit  
 2662  
 Page 1 of 1

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09/252,925Applicant(s)/Patent Under  
Reexamination  
OHNISHI ET AL.Examiner  
Hanh NguyenArt Unit  
2662

Page 1 of 1

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		Examiner Hanh Nguyen	Art Unit 2662	Page 1 of 1

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